Contribution ID: **35** Contribution code: **THPD045** Type: **Poster Presentation**

Integration of microchannel plate delay line detector in SXP instrument and Karabo control system at European XFEL

Thursday 25 September 2025 16:15 (1h 30m)

The Soft X-Ray Port (SXP) instrument at European X-Ray Free Electron Laser (EuXFEL) facility is designed to provide a flexible environment for time and spin-resolved X-ray photoelectron spectroscopy (TR-XPES) experiments. Two key components of the TR-XPES experimental station are the time-of-flight (ToF) momentum microscope spectrometer and the microchannel plate delay line detector (MCP-DLD detector). This contribution describes the key steps and challenges of integration of the MCP-DLD detector at the SXP instrument and in to the Karabo control system.

Footnotes

Funding Agency

Authors: KARPICS, Ivars (European X-Ray Free-Electron Laser); Dr DOBLAS-JIMENEZ, David (European X-Ray Free-Electron Laser); Dr IZQUIERDO, Manuel (European X-Ray Free-Electron Laser)

Co-authors: MUENNICH, Astrid (European X-Ray Free-Electron Laser); Dr GRYCHTOL, Patrik (European X-Ray Free-Electron Laser); Dr HEBER, Michael (European X-Ray Free-Electron Laser); Mrs TIKHODEEVA, Ekaterina (European X-Ray Free-Electron Laser); VARDANYAN, Vahagn (European X-Ray Free-Electron Laser); TURCATO, Monica (European X-Ray Free-Electron Laser); HAUF, Steffen (European X-Ray Free-Electron Laser)

Presenter: KARPICS, Ivars (European X-Ray Free-Electron Laser)

Session Classification: THPD Posters

Track Classification: MC09: Experiment Control and Data Acquisition